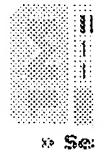


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1 An automated system for LSI fine pattern inspection based on comparison of SEM images and CAD data

Ito, M.;

 Robotics and Automation, 1995. Proceedings., 1995 IEEE International Conference on , Volume: 1 , 21-27 May 1995
 Pages:544 - 549 vol.1

[\[Abstract\]](#)
[\[PDF Full-Text \(504 KB\)\]](#)
IEEE CNF

2 CAD driven high precision E-beam positioning

Kwang, K.; Wang, H.; Hu, A.; Asaki, M.; Nijima, H.;

 Test Conference, 1993. Proceedings., International , 17-21 Oct. 1993
 Pages:928 - 935

[\[Abstract\]](#)
[\[PDF Full-Text \(476 KB\)\]](#)
IEEE CNF

3 FINDER: A CAD System-Based Electron Beam Tester for Fault Diagnosis of VLSI Circuits

Kuji, N.; Tamama, T.; Nagatani, M.;

 Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on , Volume: 5 , Issue: 2 , April 1986
 Pages:313 - 319

[\[Abstract\]](#)
[\[PDF Full-Text \(1008 KB\)\]](#)
IEEE JNL

4 Three-dimensional wound surface area calculations with a CAD surface element model

Tuch, D.S.; Lee, R.C.;

Biomedical Engineering, IEEE Transactions on , Volume: 45 , Issue: 11 , Nov.

Pages:1397 - 1400

[\[Abstract\]](#) [\[PDF Full-Text \(160 KB\)\]](#) IEEE JNL

5 Conductive adhesives for high-frequency applications

Sihlbom, R.; Dernevik, M.; Lai, Z.; Starski, P.; Liu, J.;

The First IEEE International Symposium on Polymeric Electronics Packaging , Oct. 1997

Pages:123 - 130

[\[Abstract\]](#) [\[PDF Full-Text \(624 KB\)\]](#) IEEE CNF

6 Identification and removal of defects on silicon wafer processed with rinse with/without megasonics in DI water

Heui-Gyun Ahn; Sang-Young Kim; Jeong-Gun Lee;

VLSI and CAD, 1999. ICVC '99. 6th International Conference on , 26-27 Oct.

Pages:459 - 462

[\[Abstract\]](#) [\[PDF Full-Text \(244 KB\)\]](#) IEEE CNF

7 Utilizing an integrated yield management system to improve the return on investment in IC manufacturing

Castrucci, P.; Dickerson, G.; Bakker, D.;

Semiconductor Manufacturing Science Symposium, 1991. ISMSS 1991., IEEE, International , 20-22 May 1991

Pages:25 - 29

[\[Abstract\]](#) [\[PDF Full-Text \(492 KB\)\]](#) IEEE CNF

8 Conductive adhesives for high-frequency applications

Sihlbom, R.; Dernevik, M.; Lai, Z.; Starski, J.P.; Liu, J.;

Components, Packaging, and Manufacturing Technology, Part A, IEEE Transactions on [see also Components, Hybrids, and Manufacturing Technology, IEEE Transactions on] , Volume: 21 , Issue: 3 , Sept. 1998

Pages:469 - 477

[\[Abstract\]](#) [\[PDF Full-Text \(312 KB\)\]](#) IEEE JNL

9 Digital processing of VLSI circuit images obtained from a scanning electron microscope

Zolghadrasli, A.;

Circuits and Systems, IEEE Transactions on , Volume: 37 , Issue: 6 , June 19

Pages:824 - 827

[\[Abstract\]](#) [\[PDF Full-Text \(296 KB\)\]](#) IEEE JNL

10 Electrically conductive adhesives at microwave frequencies

Dernevik, M.; Sihlbom, R.; Axelsson, K.; Zonghe Lai; Johan Liu; Starski, P.;

Electronic Components and Technology Conference, 1998. 48th IEEE , 25-28 1998

Pages:1026 - 1030

[\[Abstract\]](#) [\[PDF Full-Text \(552 KB\)\]](#) IEEE CNF

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